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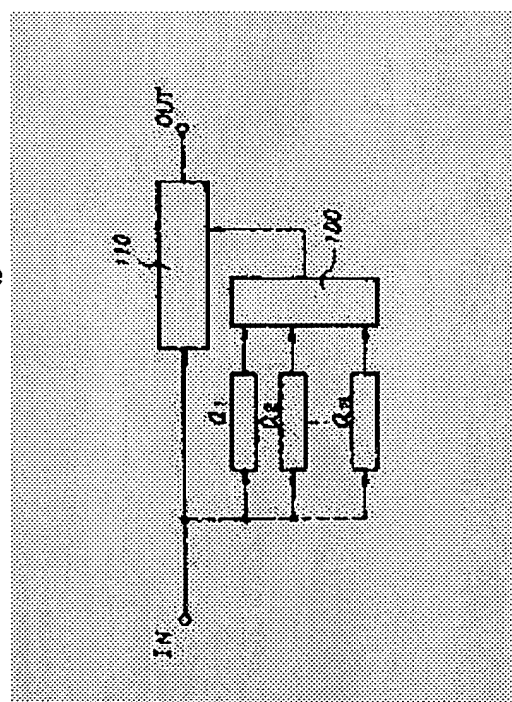
(54) DETECTING CIRCUIT FOR SPOT FLAW OF SOLID-STATE IMAGE PICKUP ELEMENT

(57)Abstract:

PURPOSE: To detect a very small level of flaw by finding a pixel having a larger or smaller output than a prescribed quantity compared with the output of the peripheral pixel out of the pixels in a regulated area.

CONSTITUTION: A video signal from a solid-state image pickup element (not shown in a figure) which prepares a scanning mechanism where a pixel for a photoelectric conversion is arranged in a matrix-shaped and a charge stored at the pixel is read out in order is inputted from a terminal IN and is supplied to detecting circuits 91, 92, ~ and 9n. A circuit t which detects a difference between pixels existing adjacent to the side direction to up and down directions and keeps a correlation between the pixels is prepared at each of detecting circuits 91, 92, ~ and 9n. The outputs from the circuits are compared and calculated at an arithmetic circuit 100

and the presence/absence of the flaw is discriminated. And a flawed pixel is corrected at a correcting circuit 110 and is outputted from a terminal OUT. Thus, the same level of the flaw in a video signal or below can be detected.



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